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Front Matter: Volume 10995

, "Front Matter: Volume 10995," Proc. SPIE 10995, Pattern Recognition and Tracking XXX, 1099501 (16 August 2019); doi: 10.1117/12.2536371

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Event: SPIE Defense + Commercial Sensing, 2019, Baltimore, MD, United States

PROCEEDINGS OF SPIE

Pattern Recognition and Tracking XXX

Mohammad S. Alam
Editor

15–16 April 2019
Baltimore, Maryland, United States

Sponsored and Published by
SPIE

Volume 10995

Proceedings of SPIE 0277-786X, V. 10995

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Pattern Recognition and Tracking XXX, edited by Mohammad S. Alam, Proc. of SPIE Vol. 10995,
1099501 · © 2019 SPIE · CCC code: 0277-786X/19/\$18 · doi: 10.1117/12.2536371

Proc. of SPIE Vol. 10995 1099501-1

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Author(s), "Title of Paper," in *Pattern Recognition and Tracking XXX*, edited by Mohammad S. Alam, Proceedings of SPIE Vol. 10995 (SPIE, Bellingham, WA, 2019) Seven-digit Article CID Number.

ISSN: 0277-786X

ISSN: 1996-756X (electronic)

ISBN: 9781510626553

ISBN: 9781510626560 (electronic)

Published by

SPIE

P.O. Box 10, Bellingham, Washington 98227-0010 USA

Telephone +1 360 676 3290 (Pacific Time) · Fax +1 360 647 1445

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Contents

v *Authors*
vii *Conference Committee*

SESSION 1 NOVEL PATTERN RECOGNITION TECHNIQUES

- 10995 02 **Improved visible to IR image transformation using synthetic data augmentation with cycle-consistent adversarial networks (Invited Paper)** [10995-1]
- 10995 04 **Neural network in a multi-agent system for line detection task in images** [10995-3]
- 10995 05 **Target tracking and classification directly in compressive measurement for low quality videos** [10995-4]
- 10995 06 **Compressive object tracking and classification using deep learning for infrared videos** [10995-5]

SESSION 2 TARGET TRACKING AND CLASSIFICATION

- 10995 07 **Small target detection for search and rescue operations using distributed deep learning and synthetic data generation** [10995-6]
- 10995 08 **Automatic pavement crack classification on two-dimensional VIAPIX images** [10995-7]
- 10995 09 **Robust infrared target tracking using thermal information in mean-shift** [10995-8]

SESSION 3 CORRELATION BASED RECOGNITION

- 10995 0B **Taking correlation from 2D to 3D: optical methods and performance evaluation (Invited Paper)** [10995-10]
- 10995 0C **Nonparametric kernel smoothing classification to enhance optical correlation decision performances** [10995-11]
- 10995 0E **Hardware design of correlation filters for target detection** [10995-13]
- 10995 0F **Wireless charging pad detection and alignment using a fisheye camera for electric vehicles** [10995-14]

SESSION 4 DEEP LEARNING BASED RECOGNITION

- 10995 0G **Suitability of features of deep convolutional neural networks for modeling somatosensory information processing** [10995-16]
- 10995 0I **Optimized training of deep neural network for image analysis using synthetic objects and augmented reality** [10995-18]
- 10995 0K **Actionable surveillance identification (ASI)** [10995-20]

SESSION 5 ADVANCED RECOGNITION TECHNIQUES

- 10995 0L **Robust detection and removal of dust artifacts in retinal images via dictionary learning and sparse-based inpainting** [10995-21]
- 10995 0N **Enhanced target recognition employing spatial correlation filters and affine scale invariant feature transform** [10995-23]
- 10995 0P **Optimization of the jamming signal parameters for conical-scan systems** [10995-25]
- 10995 0Q **Underwater image quality improvement approach based on an adapted Gabor multi-channels filtering** [10995-26]
- 10995 0R **Classroom engagement evaluation using computer vision techniques** [10995-31]

POSTER SESSION

- 10995 0S **Automated detection and classification for early stage lung cancer on CT images using deep learning** [10995-27]
- 10995 0T **A crowd counting method based on multi-column dilated convolutional neural network** [10995-28]
- 10995 0U **A Chinese acoustic model based on convolutional neural network** [10995-29]
- 10995 0V **Deep network based 3D hand keypoints prediction from single RGB images** [10995-30]
- 10995 0W **Generative adversarial networks based super resolution of satellite aircraft imagery** [10995-34]

Authors

Numbers in the index correspond to the last two digits of the seven-digit citation identifier (CID) article numbering system used in Proceedings of SPIE. The first five digits reflect the volume number. Base 36 numbering is employed for the last two digits and indicates the order of articles within the volume. Numbers start with 00, 01, 02, 03, 04, 05, 06, 07, 08, 09, 0A, 0B...0Z, followed by 10-1Z, 20-2Z, etc.

Abeywickrema, U., 0B	Overhani, Yousri, 08
Akbar, Naeem, 0E	OuldAmer, K., 0Q
Alam, Mohammad S., 0B, 0S, 0T, 0U	Rehman, Haseeb ur, 0E
Alfalou, Ayman, 08, 0C, 0Q	Rehman, Saad, 0E, 0N
Aron, Michaël, 0C	Şahingil, Mehmet Cihan, 0P
Babayan, P. V., 04	Sang, Jun, 0S, 0T, 0U
Banerjee, P. P., 0B	Sang, Nong, 0V
Barrios, Erik, 0L	Saumard, Matthieu, 0C
Bell, Christopher R., 0K	Shubin, N. Yu., 04
Birch, Phil, 0F, 0N	Sierra, Enrique, 0L
Blackwell, William, 0R	Tan, Jinghan, 0T
Bordbar, B., 0B	Tehsin, Sara, 0E
Boudraa, A. O., 0Q	Tran, Trac, 05, 06
Cai, Bin, 0U	Van Haneghan, James, 0R
Cao, L., 0B	Wang, Jialong, 0V
Chatwin, Chris, 0F, 0N	Wu, Weiqun, 0T
Chin, Jonathan, 0W	Xia, Xiaofeng, 0T
Chou, Bryan, 05, 06	Xiang, Hong, 0S
Chow, Edward, 07	Yang, Jonathan, 05, 06
Desthieux, Marc, 08	Yang, Li, 0U
Duraisamy, Prakash, 0R	Young, Rupert C. D., 0E, 0F, 0N
El Bouz, Marwa, 08, 0C, 0Q	Yu, Kevin, 02
Eldin, Sarah, 02, 07, 0I	Yun, Kyoungsik, 02, 07, 0I
Favorov, Oleg V., 0G	Yun, Sungmin, 09
G., Murugesan, 0R	Zhang, Qian, 0U
Gardezi, Akber, 0N	Zhou, H., 0B
Guerrero, David, 0F	
Hjjami, J., 0Q	
Huyen, Alexander, 02, 07, 0I	
Jackson, Steve, 0R	
Javed, Nauman, 0F	
K.S., Tamilselvan, 0R	
Kaddah, Wissam, 08	
Khoury, J., 0B	
Kim, Doyoung, 07	
Kim, Sungho, 09	
Kursun, Olcay, 0G	
Kwan, Chimam, 05, 06	
Lu, Thomas, 02, 07, 0I	
Macleod, Iain, 0K	
Malik, Usman, 0N	
Marrugo, Andrés G., 0L	
Mehmood, Asif, 0W	
Millán, María S., 0L	
Nasrullah, 0S	
Nehmetallah, G., 0B	
Nguyen, Luan, 02, 07, 0I	
Nguyen, Tuan, 07	
Osborne, Joseph, 02, 0I	

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(United States)
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Session Chairs

- 1 Novel Pattern Recognition Techniques
Mohammad S. Alam, Texas A&M University-Kingsville (United States)
- 2 Target Tracking and Classification
Vahid R. Riasati, Raytheon Space and Airborne Systems
(United States)
- 3 Correlation Based Recognition
Vijayan K. Asari, University of Dayton (United States)
- 4 Deep Learning Based Recognition
Thomas T. Lu, Jet Propulsion Laboratory (United States)

- 5 Advanced Recognition Techniques
 Asif Mehmood, Air Force Research Laboratory (United States)